METHOD AND APPARATUS FOR TESTING INTEGRATED CIRCUITS

ABSTRACT OF THE DISCLOSURE

A distributed operating system for a semiconductor test system, such as automated test equipment (ATE), is described. The operating system includes a host operating system for enabling control of one or more site controllers by a system controller. One or more local operating systems, each associated with a site controller, enable control of one or more test modules by an associated site controller. Each test module performs testing on a corresponding device-under-test at a test site.